Welcome to Galaxy Examinator reports

Date: Mon Sep 2 23:02:09 2024
Product :
LotID :

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Tests Statistics

Test	Name	Type	Low L.	High L.	Source	Execs	Fails	Mean	Sigma	Cp	Cpk	Yield
0	Functional_T1	F	n/a .	n/a .	Summary	1	0	n/a .	n/a .	n/a .	n/a .	100.00 %
1	Functional_T2	F	n/a .	n/a .	Summary	1	0	n/a .	n/a .	n/a .	n/a .	100.00 %
2	Functional_T3	F	n/a .	n/a .	Summary	1	0	n/a .	n/a .	n/a .	n/a .	100.00 %
3	PinPMU p20	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
4	PinPMU p21	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
5	PinPMU p22	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
6	PinPMU p23	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
7	PinPMU p40	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
8	PinPMU p41	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
9	PinPMU p42	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
10	PinPMU p43	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
11	PinPMU p50	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
12	PinPMU p51	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
13	PinPMU p52	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
14	PinPMU p53	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
15	PinPMU p60	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
16	PinPMU p61	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
17	PinPMU p62	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
18	PinPMU p63	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
19	PinPMU p70	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
20	PinPMU p71	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
21	PinPMU p72	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
22	PinPMU p73	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
23	PinPMU cs	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
24	PinPMU prog	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
25	SeqLeakage1 p20	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
26	SeqLeakage1 p21	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
27	SeqLeakage1 p22	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
28	SeqLeakage1 p23	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
29	SeqLeakage2 cs	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
30	SeqLeakage2 prog	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
31	VBT_outpleakage1 p40	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
Test	Name	Type	Low L.	High L.	Source	Execs	Fails	Mean	Sigma	Cp	Cpk	Yield
32	VBT_outpleakage1 p41	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
33	VBT_outpleakage1 p42	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
34	VBT_outpleakage1 p43	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
35	VBT_outpleakage1 p50	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
36	VBT_outpleakage1 p51	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %

37	VBT_outpleakage1 p52	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
38	VBT_outpleakage1 p53	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
39	VBT_outpleakage1 p60	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
40	VBT_outpleakage1 p61	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
41	VBT_outpleakage1 p62	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
42	VBT_outpleakage1 p63	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
43	VBT_outpleakage1 p70	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
44	VBT_outpleakage1 p71	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
45	VBT_outpleakage1 p72	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
46	VBT_outpleakage1 p73	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
47	OutputZ_leak_vbt1 p40	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
48	OutputZ_leak_vbt1 p41	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
49	OutputZ_leak_vbt1 p42	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
50	OutputZ_leak_vbt1 p43	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
51	OutputZ_leak_vbt1 p50	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
52	OutputZ_leak_vbt1 p51	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
53	OutputZ_leak_vbt1 p52	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
54	OutputZ_leak_vbt1 p53	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
55	OutputZ_leak_vbt1 p60	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
56	OutputZ_leak_vbt1 p61	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
57	OutputZ_leak_vbt1 p62	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
58	OutputZ_leak_vbt1 p63	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
59	OutputZ_leak_vbt1 p70	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
60	OutputZ_leak_vbt1 p71	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
61	OutputZ_leak_vbt1 p72	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
62	OutputZ_leak_vbt1 p73	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
63	Functional_T4	F	n/a .	n/a .	Summary	1	0	n/a .	n/a .	n/a .	n/a .	100.00 %
Test	**Name**	**Type**	**Low L.**	**High L.**	**Source**	**Execs**	**Fails**	**Mean**	**Sigma**	**Cp**	**Cpk**	**Yield**
64	icc_static_vbt11 vcc	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
65	Icc_dynamic vcc	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
67	Functional_T5	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
68	Functional_T5	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
70	Functional_T6	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
71	Functional_T6	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
72	Functional_T6	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
73	Functional_T7	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
74	Functional_T7	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
76	Functional_T8	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
77	Functional_T8	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
78	Functional_T8	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %

Pareto of Tests Cp

Test	Name	Cp	Test Cp Chart

Shows all Cp <= 1.7 (Defined in Options , section 'Pareto/Define Cp cut−off limit')

Pareto of Tests Cpk

Test	Name	Cpk	Test Cpk Chart

Shows all Cpk <= 1.3 (Defined in Options , section 'Pareto/Define Cp cut−off limit')

Pareto of Tests failures

Test	Name	Failing Bin	Failures count	Yield Loss	Fail contribution	Test Fail rate	Failures Chart
3	PinPMU p20	–	1	100.0 %	n/a	n/a	
4	PinPMU p21	–	1	100.0 %	n/a	n/a	
5	PinPMU p22	–	1	100.0 %	n/a	n/a	
6	PinPMU p23	–	1	100.0 %	n/a	n/a	
7	PinPMU p40	–	1	100.0 %	n/a	n/a	
8	PinPMU p41	–	1	100.0 %	n/a	n/a	
9	PinPMU p42	–	1	100.0 %	n/a	n/a	
10	PinPMU p43	–	1	100.0 %	n/a	n/a	
11	PinPMU p50	–	1	100.0 %	n/a	n/a	
12	PinPMU p51	–	1	100.0 %	n/a	n/a	
13	PinPMU p52	–	1	100.0 %	n/a	n/a	
14	PinPMU p53	–	1	100.0 %	n/a	n/a	
15	PinPMU p60	–	1	100.0 %	n/a	n/a	
16	PinPMU p61	–	1	100.0 %	n/a	n/a	
17	PinPMU p62	–	1	100.0 %	n/a	n/a	
18	PinPMU p63	–	1	100.0 %	n/a	n/a	
19	PinPMU p70	–	1	100.0 %	n/a	n/a	
20	PinPMU p71	–	1	100.0 %	n/a	n/a	
21	PinPMU p72	–	1	100.0 %	n/a	n/a	
22	PinPMU p73	–	1	100.0 %	n/a	n/a	
23	PinPMU cs	–	1	100.0 %	n/a	n/a	
24	PinPMU prog	–	1	100.0 %	n/a	n/a	
64	icc_static_vbt11 vcc	–	1	100.0 %	n/a	n/a	

Test	Name	Failing Bin	Failures count	Yield Loss	Fail contribution	Test Fail rate	Failures Chart
65	Icc_dynamic vcc	–	1	100.0 %	n/a	n/a	
72	Functional_T6	–	1	100.0 %	n/a	n/a	
78	Functional_T8	–	1	100.0 %	n/a	n/a	
–	**Cumul. of failures**	–	**26**	**100.0 %**	**0.0 %**	**0.0 %**	

–– Yield loss: number of failed test executions / number of parts
–– Fail contribution: number of failed test executions / number of parts failed
–– Test Fail rate: number of failed test executions / number of test executions

Pareto of Functional Failure Signatures (pins tested in parallel)

Total devices tested: **1**
Total patterns detected: **0**

Fail count	% of failures	% of tested	Functional Failure signatures (tested pins failing together)

Shows first 25 % of the failure signatures (Defined in Options, section 'Pareto/Define Failure Signatures cut−off limit')
No Functional failure signature detected
Possible root cause: The 'Options/Data processing/Multi−results...' option is set to 'merge' instead of 'no merge'

Pareto of Parametric Failure Signatures (tests failing concurrently)

Pareto of Software Bins

Software Binning	Bin Name	Count	Percentage	Software Binning Chart
101	–	1	100.0 %	
Cumul.	**Cumul.**	**1**	**100.0%**	

Pareto of Hardware Bins

Hardware Binning	Bin Name	Count	Percentage	Hardware Binning Chart
5	–	1	100.0 %	
Cumul.	**Cumul.**	**1**	**100.0%**	

Wafermaps & Strip Maps

Map type	Show Software bins
Devices tested (with retests)	1

List of Individual Maps

Top 10 Software Binning	101
Color	
Pass/Fail	–
Percentage	100.0%
Total count	1

Map style	WAFER map (parts tested are DIES)
Total physical parts tested	0
Parts processed	All Data / parts (any Bin)
Data from Sites	All sites
Warning	No Wafermap data available

Software Binning Summary

Software Binning	Bin Name	Pass/ Fail	Total count	Percentage	Software Binning Chart
101	–	–	1	100.0 %	
ALL Bins	**ALL Bins**	–	**1**	**100.0 %**	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Hardware Binning Summary

Hardware Binning	Bin Name	Pass/ Fail	Total count	Percentage	Hardware Binning Chart
5	–	–	1	100.0 %	
ALL Bins	**ALL Bins**	**–**	**1**	**100.0 %**	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Message Log

No log message to report

Global Information

Report from	Teradyne–Examinator–Pro+ – V8.1.5 – www.galaxysemi.com
Report created	Mon Sep 02 23:02:09 2024
Data processed	4.1 KB (4181 bytes)
Processing time	0.36 second
Processing speed	11.4 KB/sec
Examinator expires	Sat Sep 2 2034
(null)	–
File name	C:/Users/rahmana/OneDrive – Teradyne/Desktop/New Hire/New Hire Tech/UFP New Hire Train/Project 1/i8243/online/rahmana_i8243_p1.igxl_sum_09022024_225919.std
Tests mapping file	n/a
Setup time	Mon Sep 02 22:01:01 2024
Start time	Mon Sep 02 22:01:01 2024

End time	Mon Sep 02 22:01:01 2024
Test duration	n/a .
Product	n/a
Program	rahmana_i8243_p1.igxl
Revision	n/a
Lot	n/a
Sub−Lot	n/a
WaferID	n/a
Parts processed	All Data / parts (any Bin)
Data from Sites	All sites
Test time (GOOD parts)	n/a .
Test time (ALL parts)	n/a .
Average test time	n/a .
Total parts tested	1 − Includes parts retested (if any)
Good parts (Yield)	0 (0.00%) − Includes parts retested (if any)
Bad parts (Yield loss)	1 (100.00%) − Includes parts retested (if any)
Parts retested	n/a .
Parts aborted	0 (0.00%)
(null)	−
STDF Version	4.0
Tester name	8FJ3M34
Tester type	UltraFLEXplus
Station	1
Part type	n/a
Operator	rahmana
Exec_type	IG−XL
Exec_version	10.40.10_uflx
TestCode	n/a
Test Temperature	n/a
User Text	n/a
Aux_file	n/a
Package type	n/a
Per_freq	n/a
Spec_name	n/a
Spec_version	n/a
Family ID	n/a
Date code	n/a
Design Rev	n/a

Facility ID	n/a
Floor ID	n/a
Proc ID	n/a
Flow ID	n/a
Setup ID	n/a
Eng ID	n/a
ROM code	n/a
Serial #	n/a
Super user name	n/a
Handler/Prober	n/a
(null)	–
Site details	Site# 0

Global Options

Test# policy	Never merge tests with identical test number if test name not matching
Data Cleaning	None (keep all data)
Statistics computation	From samples data (if any), otherwise from summary
Binning computation	From summary data (if any), otherwise from samples
Cp,Cpk computation	Use standard Sigma formula
Mean drift formula	Percentage of value drift